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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Schneegans, *et al.* Docket No.: 2001 P 17353 US
Serial No.: 10/826,954 Art Unit: 2829
Filed: April 15, 2004 Examiner: Jimmy Nguyen
For: Probe Needle for Testing Semiconductor Chips and Method for Producing
Said Probe Needle


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Respectfully submitted,


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